



QA Technology Company, Inc.

# A p p l i c a t i o n s N o t e

## Long Stroke 40 Series Probes

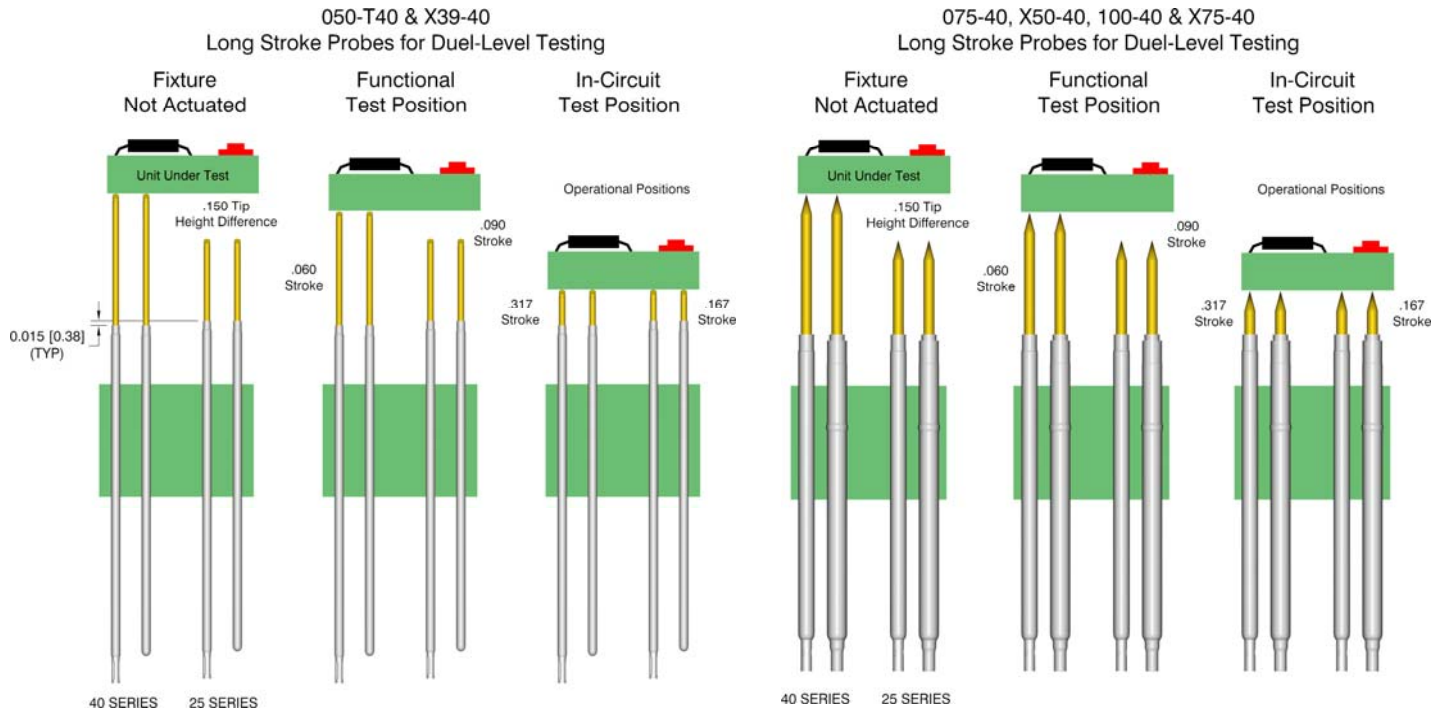
Document# ANQ012

Rev B

ECN# 3194

Page 1 of 1

QA Technology's .400 [10.16] series long-stroke 40 series probes are designed for use in dual-level (Functional/In-Circuit) test fixtures. The .400 [10.16] series long-stroke probes are easily mixed with their .250 [6.35] standard-stroke counterparts from same series. Long-stroke and standard-stroke probes with the same center spacing install in identical sockets, mounted at the same set height (see note below). This allows the probes to be interchanged freely from one socket to another as test needs dictate.



As shown above, the long-stroke probe tips are .150" higher than neighboring standard-stroke tips when the fixture is not actuated. In the functional test position, the long-stroke probes are deflected .060", leaving .090" clearance to the tips of the standard-stroke probes. During in-circuit test, deflection of the long-stroke probes is .317", and the standard-stroke probes are deflected .167" (the recommended two-thirds travel position).

Note: When installing the 050-T25 sockets or X39-25 termination pins for the dual level testing, the .250 [6.35] stroke sockets terminations must be mounted .015 [.38] higher to achieve the .150 tip height difference when the fixture is not activated. Note: The "U" force spring in all .400 [10.16] stroke series is rated for .350 [8.89] stroke. See Customer drawings.

Conventional Probes		X Probes	
Standard Stroke .250 [6.35]	Long Stroke .400 [10.16]	Standard Stroke .250 [6.35]	Long Stroke .400 [10.16]
050-T25	050-T40	X39-25	X39-40
075-25	075-40	X50-25	X50-40
100-25	100-40	X75-25	X75-40